

Final Product/Process Change Notification Document #: FPCN21750X

Issue Date: 18 July 2017

Title of Change:	Qualification of ON Semiconductor facility in Carmona, Philippines as an additional Final Test Location for former AXSEM Product AX5243.				
Proposed first ship date:	30 September 2017 or earlier after customer approval				
Contact information:	Contact your local ON Semiconductor Sales Office or < <u>Tamara.Olney@onsemi.com></u>				
Samples:	Contact your local ON Semiconductor Sales Office				
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office of			.Syndergaard@onsemi.com>	
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact < PCN. Support@onsemi.com>.				
Change Part Identification:	Affected products will be identified with date code.				
Change category:	☐ Wafer Fab Change ☐ Assembly Change ☐ Test Change ☐ Other				
Change Sub-Category(s): Manufacturing Site Change/Addition Manufacturing Process Change		☐ Material Change ☐ Product specific change		☐ Datasheet/Product Doc change ☐ Shipping/Packaging/Marking ☐ Other: Tester Equipment Change	
Sites Affected: All site(s) not applicable ON Semiconductor site(s): ON Carmona, Philippines External Foundry/Subcon site(s)					
					
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TEM001092 Rev. M Page 1 of 1